Make ideas real



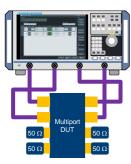
## R&S®ZNx-K100: SNP ASSISTANT

# For R&S®ZNA/ZNB/ZNBT/ZND vector network analyzers



### SNP assistant software for vector network analyzer

The SNP assistant measurement wizard intelligently guides users through all required measurements with minimal and optimized re-connection steps. Measuring an M-port multiport DUT with an N-port VNA (where M is larger than N) is useful. A measurement result with a higher order touchstone file can be conveniently generated afterwards.



#### Ideal for

High-speed interconnect

RF component measurement

Multiport antenna measurement

Key specifications	Descriptions
Supported hardware	► VNA: R&S°ZNA, R&S°ZNB, R&S°ZNBT, R&S°ZND ► Switch matrix: R&S°ZN-Z84, R&S°ZN-Z85, R&S°ZN-Z86(X)
DUT topology	<ul> <li>Pre-defined template such as QSFP/SFP/USB</li> <li>VNA port selection</li> <li>Reference impedance definition</li> </ul>
DUT structure	<ul><li>Single-ended input/output</li><li>Balanced input/output</li></ul>

Your benefit	Features
Flexible DUT topology	➤ User-defined topology  Self-defined DUT topology with intuitive structure icon  ➤ Pre-defined topology template  Select the DUT standard by technology and form factor
Easy defining test items with less effort	<ul> <li>▶ Color coding         Use color coding for each S-parameter cell to mark the data status as idealized, measured, unmeasured and imported.     </li> <li>▶ Test item shortcut         Decide which test items are to be measured via the shortcut buttons for reflection, transmission and crosstalk     </li> <li>▶ Victim and aggressor pattern         Identify near-end or far-end crosstalk from the perspective of victims and aggressors     </li> <li>▶ Import existing data         Define test items by importing existing touchstone files     </li> <li>▶ Least measurement steps</li> <li>Save test time with the step-by-step wizard guide for the least re-connections</li> </ul>
Understandable measurement result	<ul> <li>► File header includes DUT definition</li> <li>DUT topology written in the touchstone header that benefits the user to immediately understand the relationship between the port function and port number</li> <li>► High order touchstone file</li> <li>Export n<sup>th</sup> order touchstone file with n &gt; base unit port count</li> </ul>

#### Flexible topology definition



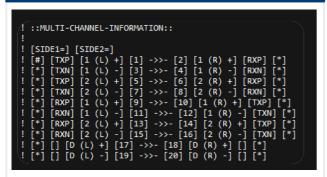
User-defined topology by adding structure icons or pre-defined topologies with technology template dropdown box

#### Test items shortcuts and S-parameter visualization



Test items can be edited via the shortcut buttons to setup reflection, transmission, near-end or far-end crosstalk or crosstalk by victim/aggressor patterns

#### Touchstone file header information

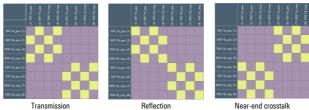


DUT topology information is clearly shown on the touchstone file header

#### Easy defining test items with V/A patterns



#### Test items can be determined by V/A buttons



Example of SFP+ cable testing: efficiently determine complex test items according to topology wiring and victim/aggressor pattern definition

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Trade names are trademarks of the owners | R&S®ZNx-K100: SNP assistant | Data without tolerance limits is not binding
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Ordering information	Material number
Description	Order No.
R&S®ZNA-K100 SNP assistant	1338.9327.02
R&S®ZNB-K100 SNP assistant	1338.9333.02
R&S®ZNBT-K100 SNP assistant	1338.9340.02
R&S®ZND-K100 SNP assistant 1)*	1338.9356.02

1) R&S°ZND-K5 or R&S°ZND-K6 full test set bi-directional option required

#### Step-by-step wizard guide



The wizard guide leads users through a measurement with minimized connection steps and optimized connections

#### **Feature highlights**

- ► Support user-defined or pre-defined DUT topologies
- ► Display S-parameter visualization
- ► Allow test item shortcuts
- ► Minimize measurement steps
- ► Feasible for high order touchstone file exports